

Inspec Direct User Guide

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Get straight to the information you need

About Inspec Direct

Inspec Direct is a powerful research tool that provides access to the Inspec Database via the Web. Designed specifically for science and engineering researchers, students, and professionals from all backgrounds, Inspec Direct allows you to quickly find and analyse information.

The Inspec Direct search interface has a number of search options. These are accessed via tabs across the top of the screen. These tabs allow you to choose between Quick Search, and Advanced Search options. Help topics are available in Inspec Direct through "Show help" menus to the right of both the Quick and Advanced search bars.

Key features

- Inspec indexed abstracts (1898 to current year)
- Two different search types: Quick and Advanced
- Help topics in platform for quick reference
- Select records to download and see count of records selected
- Download search results in text format
- Data updated weekly
- IP authentication

With Inspec Direct, users can find the relevant information to:

- Keep track of latest research
- Discover new product information
- Forecast technology and monitor industry trends
- Gain competitive intelligence
- Research basic patent information

Inspec is the leading English language abstracting and indexing service providing information from the world's literature in:

- Physics
- Electrical engineering and electronics
- Computers and control
- Mechanical and production engineering

Inspec Direct contains over 4,000 journals and 2,500 conference proceedings, as well as numerous books, reports and dissertations. The database contains over 18 million records.

Inspec Archive

Inspec Archive data are the historical scientific records produced for the Science Abstracts series of journals during the period 1898-1968, which were the precursor to the Inspec Database. Initially they were available only in printed format, but the entire collection has been digitised and is now a part of Inspec Direct.

The Archive contains:

- Over 873,700 records
- Longer abstracts than more recent material and tables, graphs, and figures from the original source document in many cases
- The original value-added indexing and classifications
- Enhancements in the form of the nearest equivalent current Inspec Controlled Indexing Terms, Inspec Thesaurus and Inspec Classification Codes
- Conference proceedings, books, journals, reports and dissertations

The Inspec Archive data represents the 176 volumes (and over 140,000 pages) of the printed Science Abstracts series of journals.

Support

A range of support options are available to help you get the best out of Inspec Direct, including an [online user guide](#), in-platform help, and in-house training or remote training sessions via the Internet can be arranged. To request training or to discuss your needs further please contact your [local Inspec office](#).

Getting Started

Accessing Inspec Direct

- Visit <https://inspec-direct-app.theiet.org/quick-search> or click on "Go to Inspec Direct" on the menu bar of the product website at: <https://inspec-direct.theiet.org>.
- If you receive an Access denied error message, then you need to check that your institution has a subscription. [Contact us](#) or [Request a Demo](#) if you are not certain.
- If your access is successful, then welcome to Inspec Direct!

You can now begin searching. You will land on the Quick Search page by default so you can start your search there or move over to the Advanced search to use the pre-filtered drop down fields.

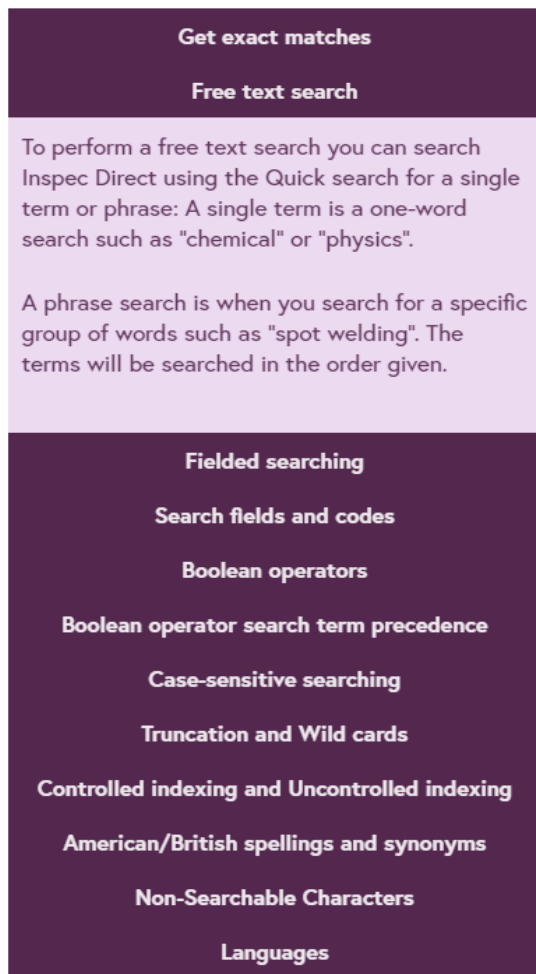
Bookmark the Inspec Direct [News](#) page to keep up to date with new features and other developments and events for Inspec Direct.

Online Help

Online help is available from the Inspec Direct [User Guide](#).

Help Tips

On the **Advanced and Quick Search** pages, there is a comprehensive list of search tips which can be accessed using the hyperlinks.



A typical Inspec record contains an English language title and descriptive abstract, together with full bibliographic details to enhance search elements, such as the Inspec Thesaurus, Classification Codes and Treatment Codes.

Below is a representative example of an Inspec record. Fields differ depending on data received for the actual records and on the document types.

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Title

Accession Number.: 10159784

Update: 2008-036

Document Type: Journal paper

Title: 2.5 V passive CMOS mixer with 20 dBm P1 dB compression

Author(s): De Backer, E.; Bauwelinck, J.; Melange, C.; Matei, E.; Ossieur, P.; Qiu, X.Z.; Vandewege, J.; Horvath, S.

Journal: Electronics Letters, vol.44, no.18, p.1067-9

Publication Date: 28 Aug. 2008

Publisher: IET, UK

ISSN: 0013-5194

JIN: BN60

CODEN: ELLEAK

DOI: 10.1049/el:20081556

Language: English

Abstract: A passive CMOS down conversion mixer with LO buffer is presented in 0.25 μm SiGe BiCMOS using a 2.5 V supply. With a 60 MHz RF signal input, measurements show that the conversion loss is 2.9 dB, the input-referred 1 dB compression point is 20 dBm and the input-referred noise is -146.8 dBm/Hz. Compared to conventional NMOS mixers, the 1 dB compression point is improved by 9.7 dB. The tradeoffs and the design of the LO buffer, which has a strong impact on the intermodulation distortion, are also presented. (8 refs.)

Treatment: Practical; Experimental

Controlled indexing: BiCMOS integrated circuits; buffer circuits; CMOS integrated circuits; Ge-Si alloys; intermodulation distortion;

micromechanical devices; passive networks; UHF mixers;

Uncontrolled indexing: passive CMOS down conversion mixer; LO buffer; BiCMOS; RF signal input; compression point; input-referred noise; NMOS mixers; intermodulation distortion; gain 9.7 dB; voltage 2.5 V; size 0.25 μm ; frequency 60 MHz; SiGe

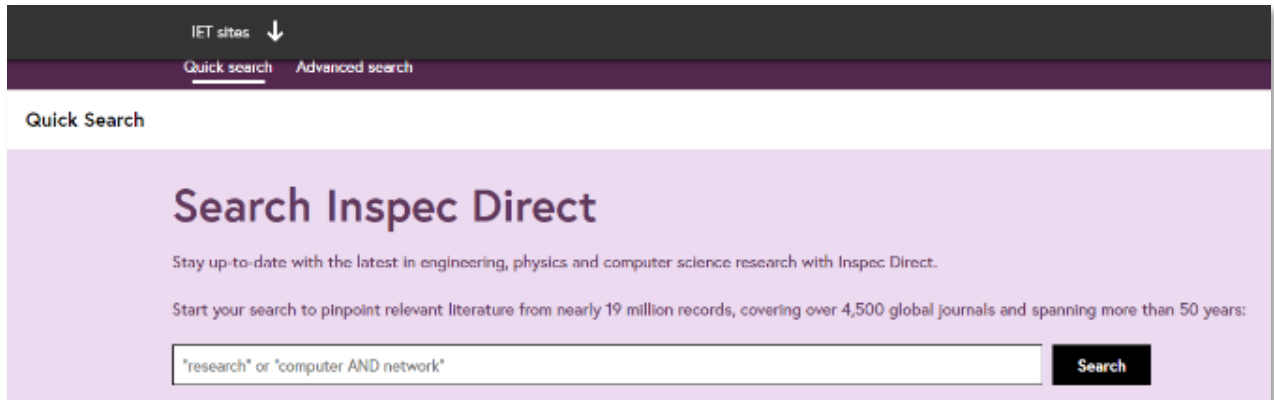
Classification: A0710C Micromechanical devices and systems; B2570K Mixed technology integrated circuits; B1250 Modulators, demodulators, discriminators and mixers; B1350 Microwave circuits and devices; B1270D Passive filters and other passive networks; B2570D CMOS integrated circuits; B5230 Electromagnetic compatibility and interference; B6120 Modulation and coding methods; B2575D Design and modelling of MEMS and NEMS devices

Numerical data indexing: gain 9.7E+00 dB; voltage 2.5E+00 V; size 2.5E-07 m; frequency 6.0E+07 Hz

Chemical indexing: SiGe/int Ge/int Si/int SiGe/bin Ge/bin Si/bin

Searching

Quick Search



Boolean operators

By using a combination of keywords (words to search for) and Boolean operators (**AND**, **OR**, **NOT**), you can narrow or broaden your searches to include or exclude particular concepts.

The **Quick Search** form will search all fields. If you wish to search in specific fields, you should use the **Advanced Search** or use the operators listed below in the section on Fielded searching using the Quick Search.

The Inspec Direct Boolean search operators are used to link search terms or fields. Depending on the operators used, your search will be broadened or narrowed:

OR operator finds records that contain at least one or more of the search terms. It is used to **broaden a search**.

AND operator finds records that contain all of the search terms and thus is used to **narrow a search**.

NOT operator finds records that contain one term but not another. It is used to **narrow a search by excluding specific terms**.

The Boolean operators must be written entirely in capital letters to work.

AND operator:

The **AND** operator is used to narrow a search by including only the specified terms for the purpose of connecting concepts.

Example

COMPUTER AND NETWORK

Only records containing both COMPUTER and NETWORK will be retrieved.

OR operator:

The OR operator is used to broaden a search by including additional terms.

Example

COMPUTER OR NETWORK

Only records containing either COMPUTER or NETWORK will be retrieved.

NOT operator:

You can enter a NOT operator in combination with the Boolean operator AND to exclude search terms and narrow your search.

Example

COMPUTER AND AIDED NOT NETWORK. Only records containing COMPUTER AND AIDED but not NETWORK will be retrieved.

Truncation/Wildcard

Truncation serves as a substitute for zero or more characters. Only right-hand truncation is allowed.

Example

To search for any word beginning with 'comput' (e.g. computer, computing, computerised, computation), enter **comput*** into the text box.

Wildcard: ? can be used to substitute a single character.

Example

To search for either computerized or computerised, you could enter **computeri?ed** into the text box.

Exact Searches

To search for an exact phrase, enclose the keywords within double quotes. In addition to their meaning within a record, some words also have a meaning in terms of searching, such as the word 'and', which is used as a Boolean operator. The word 'and' also occurs in some thesaurus terms, proper names, etc.

There are also other common words (stop words) and punctuation – that cannot be searched for directly.

To search for a phrase including the word 'and', you should enclose the phrase in double quotes, e.g. **"town and country planning"**.

Fielded searching

Inspec Direct supports fielded searching in the Quick search and Advanced Search. When performing a fielded search in the Quick search, you need to specify a field code and use the Colon (:) operator. Enter the field code followed by a colon: directly followed by the keyword you are looking for. *No spaces should be present between the colon and the search term.* For example, enter into the Quick search box, AU:Rebane to search for any document by this partial author name.

Enclose a search phrase in double quotes for exact matches to be returned in fielded search. For example, to expand the example above, you can input AU:"jonathan rebane" to search the complete author name.

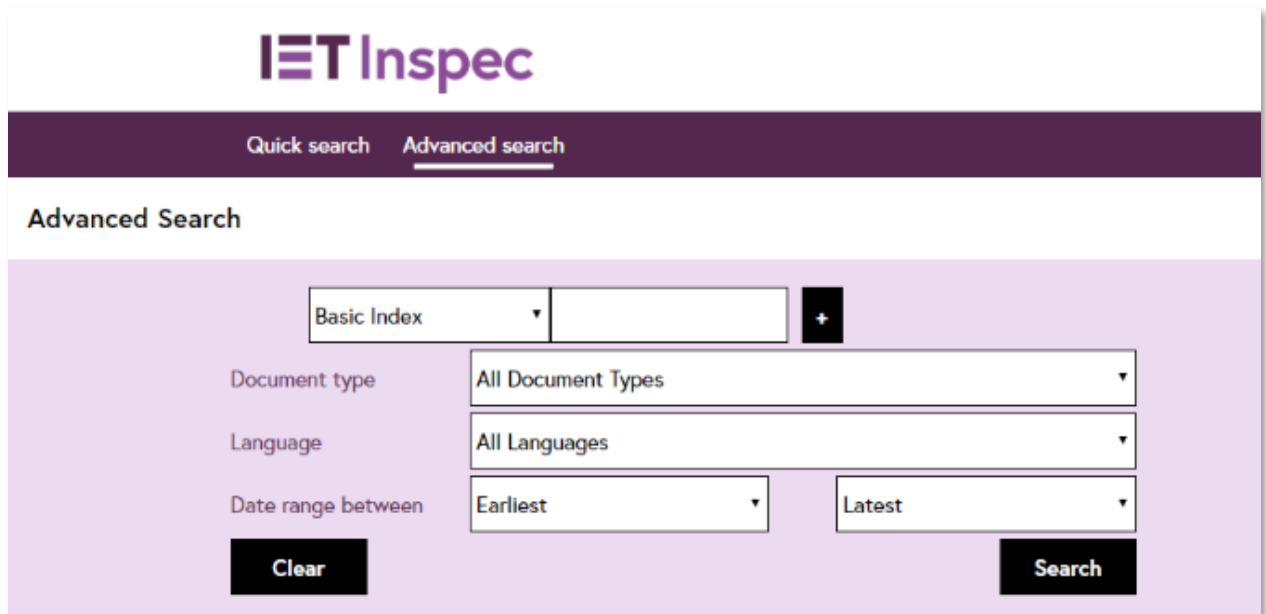
Example

Entering into the Quick search **CT:atomic force microscopy** will bring up results for Controlled Indexing term atomic force microscopy

Within the Advanced search, the fields are provided by default in a drop-down menu and can be further configured by selecting one or more Boolean operators. You can then refine your search by document type, language, or by a specific year or range of years.

See [Search Fields](#) for a list of the available fields searchable by code in the Quick search.

Advanced Search



The screenshot displays the IET Inspec Advanced Search interface. At the top, the IET Inspec logo is visible. Below it, there are two navigation options: 'Quick search' and 'Advanced search', with 'Advanced search' being the active one. The main section is titled 'Advanced Search'. It features a search bar with the text 'Basic Index' and a plus sign to its right. Below the search bar, there are three dropdown menus: 'Document type' set to 'All Document Types', 'Language' set to 'All Languages', and 'Date range between' with 'Earliest' and 'Latest' dropdowns. At the bottom of the search area, there are two buttons: 'Clear' and 'Search'.

The Advanced search in Inspec Direct allows you to limit your search by selecting index fields from a menu such as Basic Index, Author, and Controlled indexing. You can also select to add any or all of the available Boolean operators AND, OR, NOT using the plus sign available in the interface. Specific dates, date ranges, document type and Language can be selected to limit your search.

Boolean operators

Boolean operators are used to include or exclude search terms so that the number of search hits will be broadened or narrowed. In the Advanced search, these operators are already provided for selection by default. You can click the plus sign next to the Advanced search operator fields to add more Boolean operators.

The available Boolean operators are:

NOT
AND
OR

Limit By

You can restrict the results set using criteria of document type, time range, language of original document, and date range either earliest to latest or by setting a range from one specific year to another.

Example

Let's assume you are interested in papers on the subject of viscoelasticity that were published in conferences which took place in 2007.

1. Enter **viscoelastic*** into the search box.
2. Change the 'Document Type' drop-down to **Conference Paper**.
3. Select a date range from 2007 to 2007
4. Then simply click on the **'Search'** button.

Search Fields

Searchable Bibliographic fields

Fields that are directly searchable by assigned search code using the Inspec Direct Quick search or a dropdown choice in the Advance search indexes menu.

Abstract (AB): Summary of article's content; written by the document's author or, created, edited or translated by Inspec editors

Basic Index (BI): Searches the Title (TI), Abstract (AB), Controlled indexing (CT) and Uncontrolled indexing (UT) fields.

Accession Number (AN): Unique identifier for an abstract record.

Title (TI): Title of the abstract

Document Type (DN): The type of document in which the abstracted Introduction item is published, e.g. journal paper.

Language (LA): The language in which the article was written.

Publisher (PU): The name of the publisher of a book, dissertation, standard or conference proceedings.

Publication Date (PY): The year in which an article was published.

Title (TI): The title of an article from a journal, conference, book or section of a report which has been abstracted by Inspec.

Controlled indexing (CT): Any of the over 10,000 index terms from the [Inspec Thesaurus](#), with each record having at least one term (and usually several) assigned to it.

Uncontrolled indexing (UT): Significant free-language words and phrases chosen by Inspec's subject specialists which describe the subject content of an article.

Other bibliographic fields

These are fields not yet directly searchable by search code but appear visible on an Inspec record.

ISBN The International Standard Book Number of a book which has been abstracted by Inspec.

ISSN: The International Standard Serial Number of a journal.

Issue Number: The issue number within a particular volume of a journal.

Issuing Organisation: Name of the issuing organization for Dissertation, Report and Standard

Journal Title: The full journal name.

Original Patent Application Number: The application number given to a patent when it was first applied for.

Page Numbers: The full pagination of an article (e.g. "35-41") or the number of pages in the article where the full pagination is not available (e.g. "7 pp.").

Patent Assignee: The owner of a patent (either an individual or an organisation).

Patent Data: Can show Original Patent Application Numbers, Patent Numbers, Patent Assignee and Country of Original Patent Application, and Country of Patent.

Patent Number: The number given to a patent when it is finally granted.

Publication Year: The year in which an article was published.

Publication Date: The date on which an article was published.

Publication Title: The title of a non-journal publication. This includes Book Titles, Report Titles, and Conference Titles, but it does not include Journal Titles.

Publisher: The name of the publisher of a book, dissertation, standard or conference proceedings.

Report Number: The report number assigned to a report by the issuing organisation.

Report Title: - The title of a report which has been abstracted by Inspec

SICI: The Serial Item and Contribution Identifier is a numeric notation to identify serial issues and articles uniquely regardless of their distribution medium (paper, electronic, microform).

U.S. Government Clearing House Number: The number assigned to a report by the U.S. Government Clearing House.

Update: The weekly update number that is given to the set of records which is added to the Inspec Database each week.

URL: The URL (Uniform Resource Locator) or Web address of the full-text version of the article

Volume: The volume of a journal.

Inspec Indexing Subject Fields

Astronomical Object Indexing: Controlled designations for astronomical objects discussed in the document.

Chemical Indexing: Standardised data for inorganic substances and their specific roles Classification.

IPC Code (IP): International Patent Classification code, generated from the corresponding Inspec Classification Code (CC) field.

Numerical Data Indexing (various fields): Structured numeric data from the document, such as experimental parameters.

Primary Classification: Most significant Classification Codes for that item. Subfile (SF): One of the five sections of the Inspec Database, A, B, C, D, or E.

Treatment Codes: indicate the approach taken to a subject by the author of a source document

Treatment Types

Application: Assigned when a document describes the actual technique, computer program or physical effect where some specific application is described or envisaged.

Bibliographic or literature survey: Indicates documents containing a bibliography or significant number of references.

Economic aspects or market survey: Applied where the document deals with some economic or commercial aspects, e.g. cost, pricing, market forecast, etc.

General or review: this code distinguishes documents which give an overall view of a subject. It includes general approaches, overviews, state-of-the-art reviews and introductory articles.

New development: Used where a claim of novelty, in the patent sense, might be made)

Practical: Indicates that the document is meant to be of practical use, and so is likely to be of use to engineers and designers.

Product Review: Applied to product comparisons, tables and buyers' guides.

Theoretical or mathematical: Assigned when the subject matter is generally of a theoretical or mathematical nature.

Experimental: Used for documents describing an experimental method, observation or result. Includes apparatus for use in experimental work and calculations on experimental results.